

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/724,169	PARK ET AL.
	Examiner	Art Unit
	Tianjie Chen	2627

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
720	650	8/21/2006	TJ